Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/606,258	CHIN ET AL.	HIN ET AL
Examiner	Art Unit	rt Unit
Usmaan Saeed	2166	166

	SEARCHED		
Class	Subclass	Date	Examiner
707	104.1	2/13/2006	us
716	18	2/13/2006	US

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor & related case search	3/9/2006	US
East (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB)	2/13/2006	US
Plus	2/13/2006	US
Consulted Primary Examiner (Khanh Pham)	3/9/2006	US
Consulted Primary Examiner (Leslie Wong)	2/13/2006	US
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